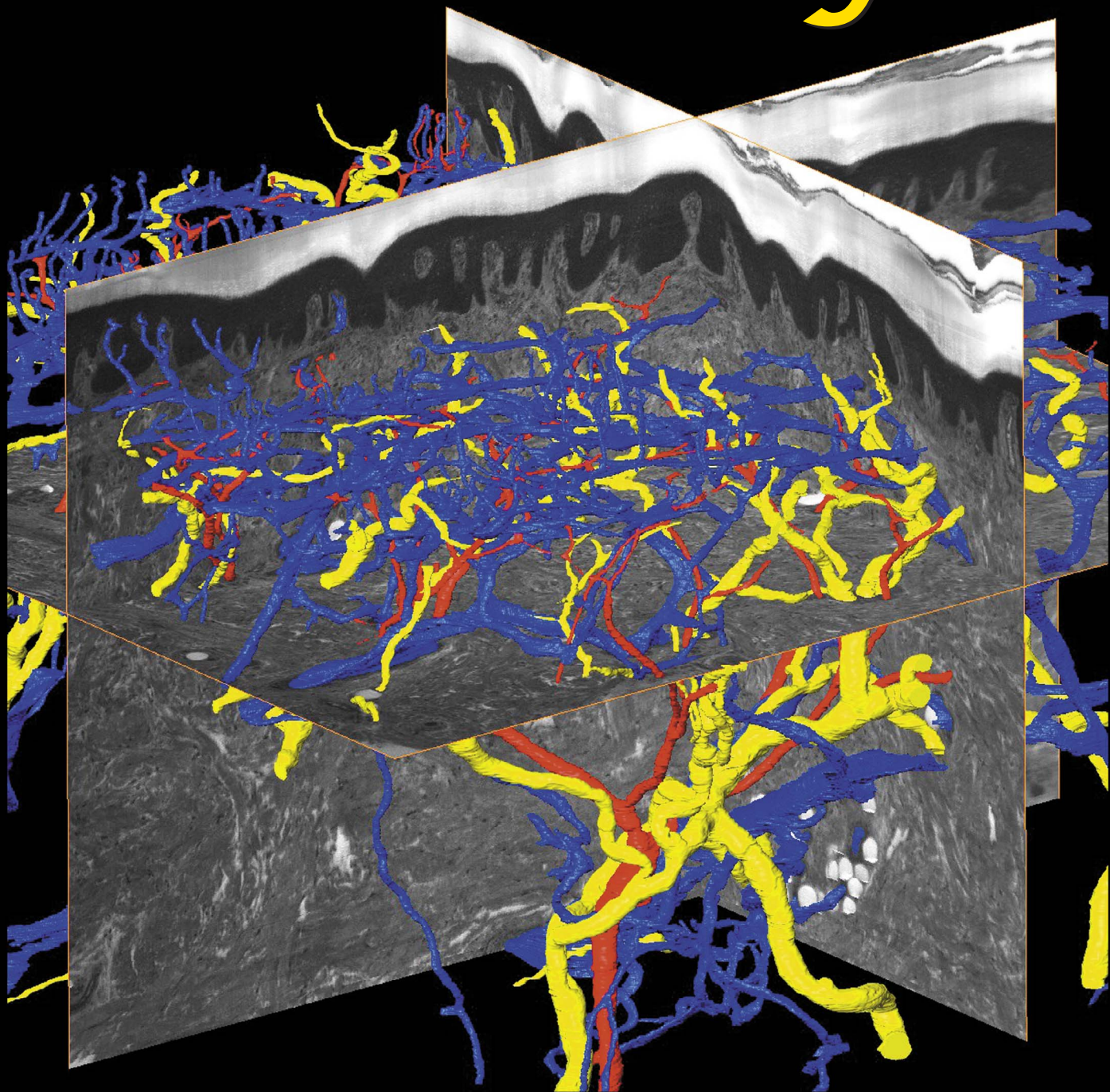


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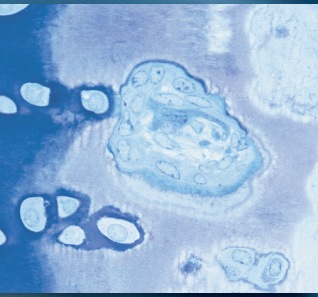
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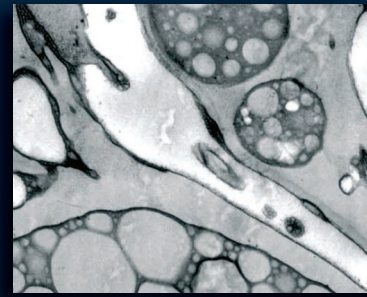
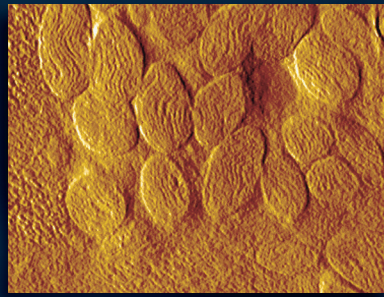
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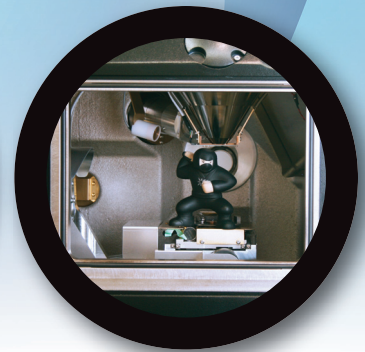
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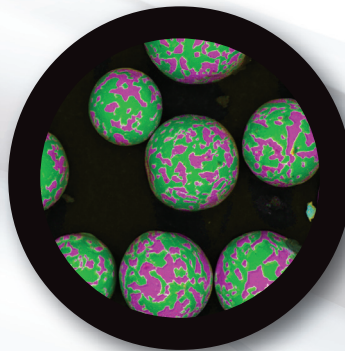
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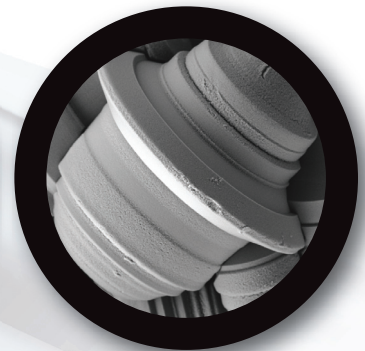
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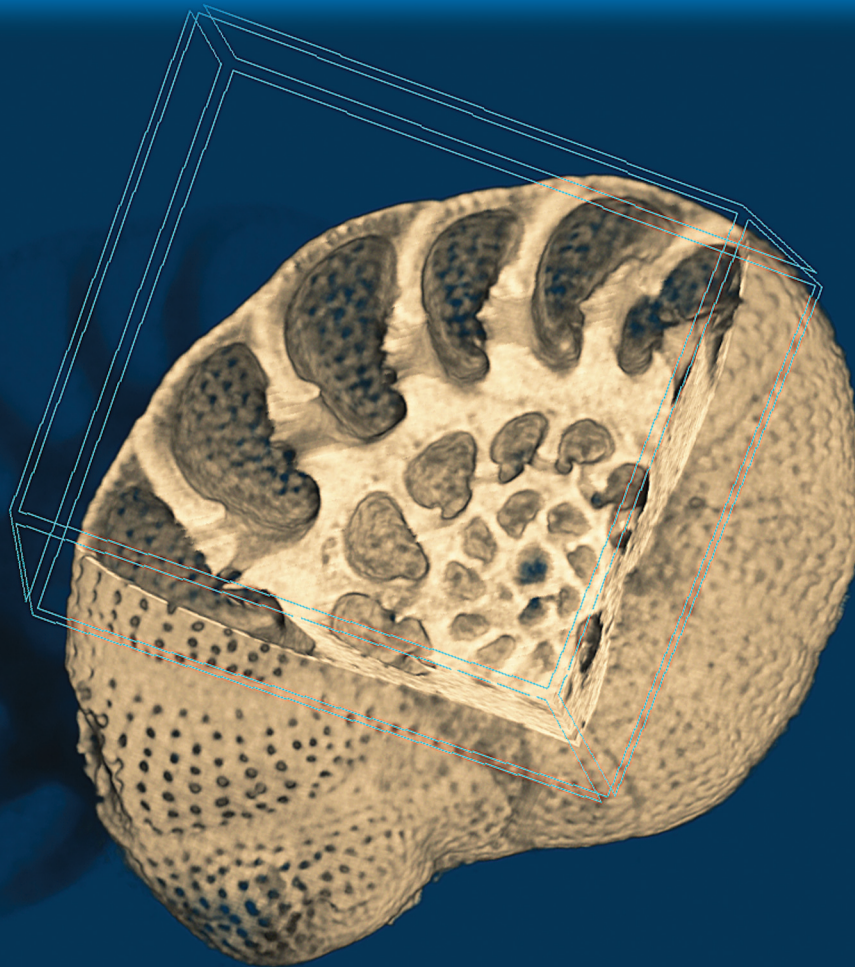


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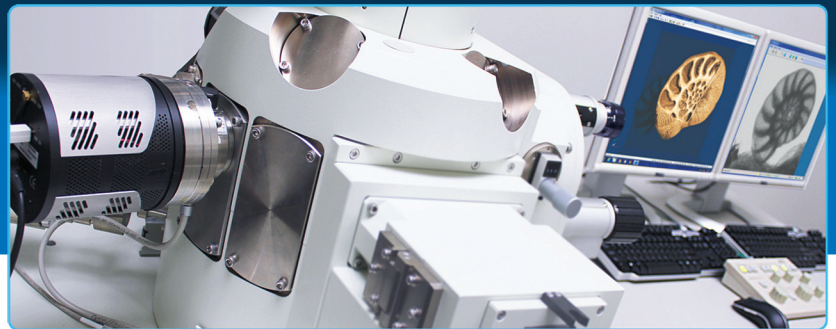
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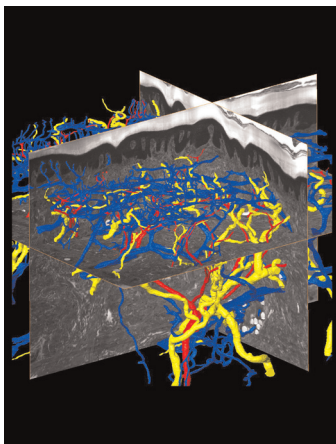
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On the Cover: 3D render of vasculature and nerves in dermis biopsy from human finger. For further information please see Geyer et al., pages 1356–1364

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Isn't it about time you had your own Digital Microscope?

Now you can with the portable, affordable uScopeMXII!

The uScopeMXII is a small digital desktop microscope you can use in your workplace or home office. It captures images from standard glass slides and sends them to your PC.

You can interactively browse slides with full control of focus, image processing, and location. You can also scan regions of

interest creating fully focused image sets.

The industry-standard USB interface makes it simple to plug in and start capturing images. It easily interfaces with your desktop or laptop PC and allows you to view and capture slide images in a wide variety of environments.

The uScopeMXII is manufactured in the United States.

Features and Benefits

■ Overview and Objective Cameras

The uScopeMXII has an objective camera for scanning and an overview camera for navigating.

■ Automatic Focus

Images are automatically focused using configurable focus algorithms.

■ Portability

At a weight of about 5 lbs., the uScopeMXII is highly portable.

■ Easy to Use

The uScope Navigator software simplifies scanning and browsing.

■ Self-Contained

The uScopeMXII is self-contained and includes the electronics, cameras, stage, and optics in a device about the size of a large external disk drive.

■ Full Imaging Control

User filters provide complete control over image processing and correction.



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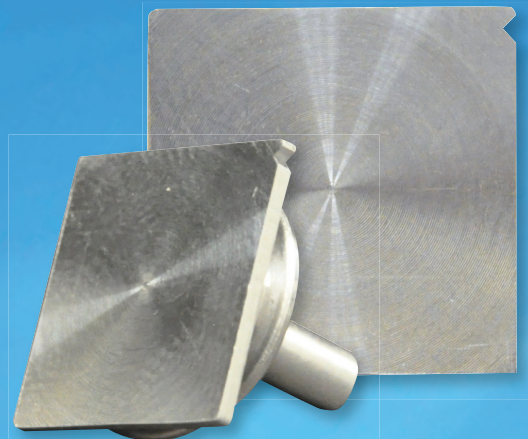
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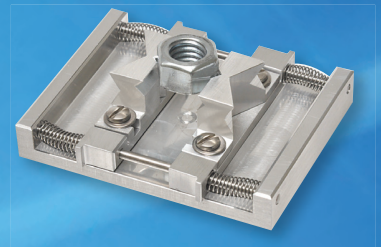
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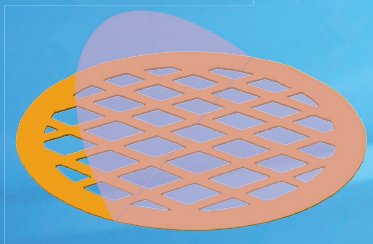
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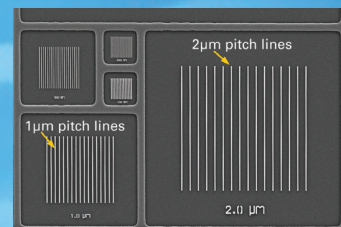
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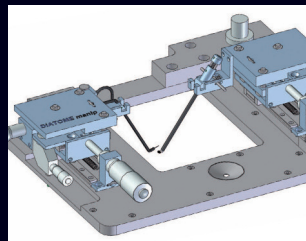
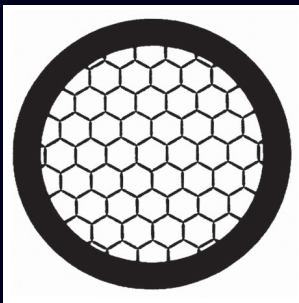


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